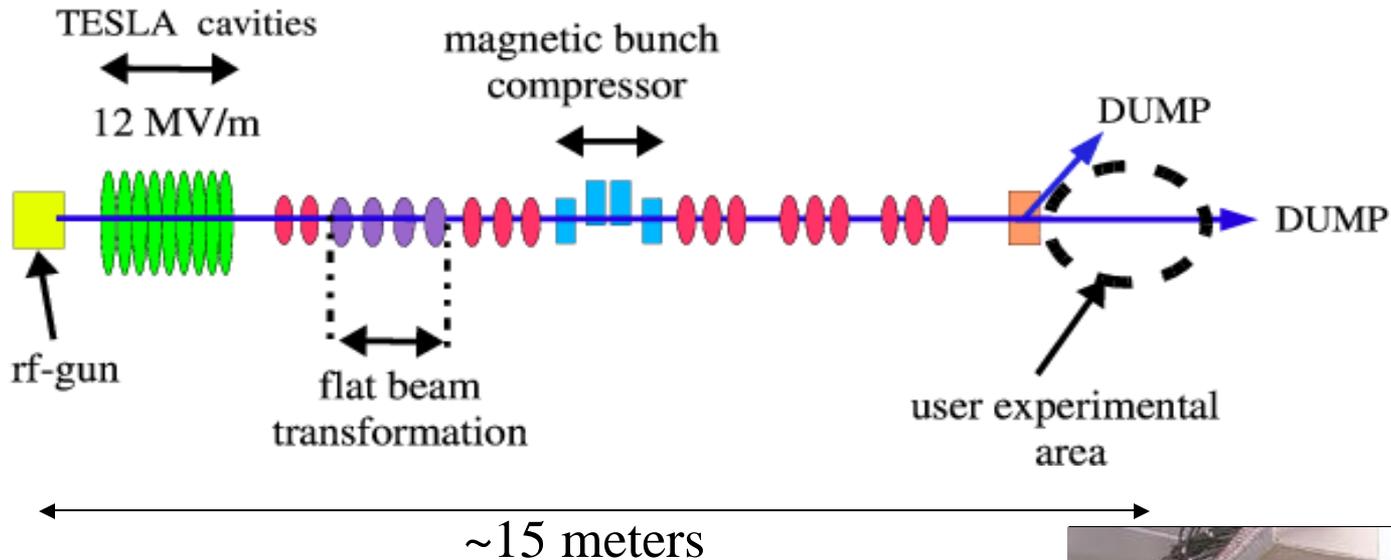


Laser Pulse Shaping and Emittance Studies

Rodion Tikhoplav

A0 PHOTOINJECTOR OVERVIEW



$E = 15 \text{ MeV}$

$Q = \text{up to } 20 \text{ nC,}$

$e = 3.0 \text{ mm-mrad (1 nC)}$

? $p/p = 0.25 \% \text{ (1 nC)}$

$I_{\text{peak}} = 75\text{-}330 \text{ A (BC off)}$

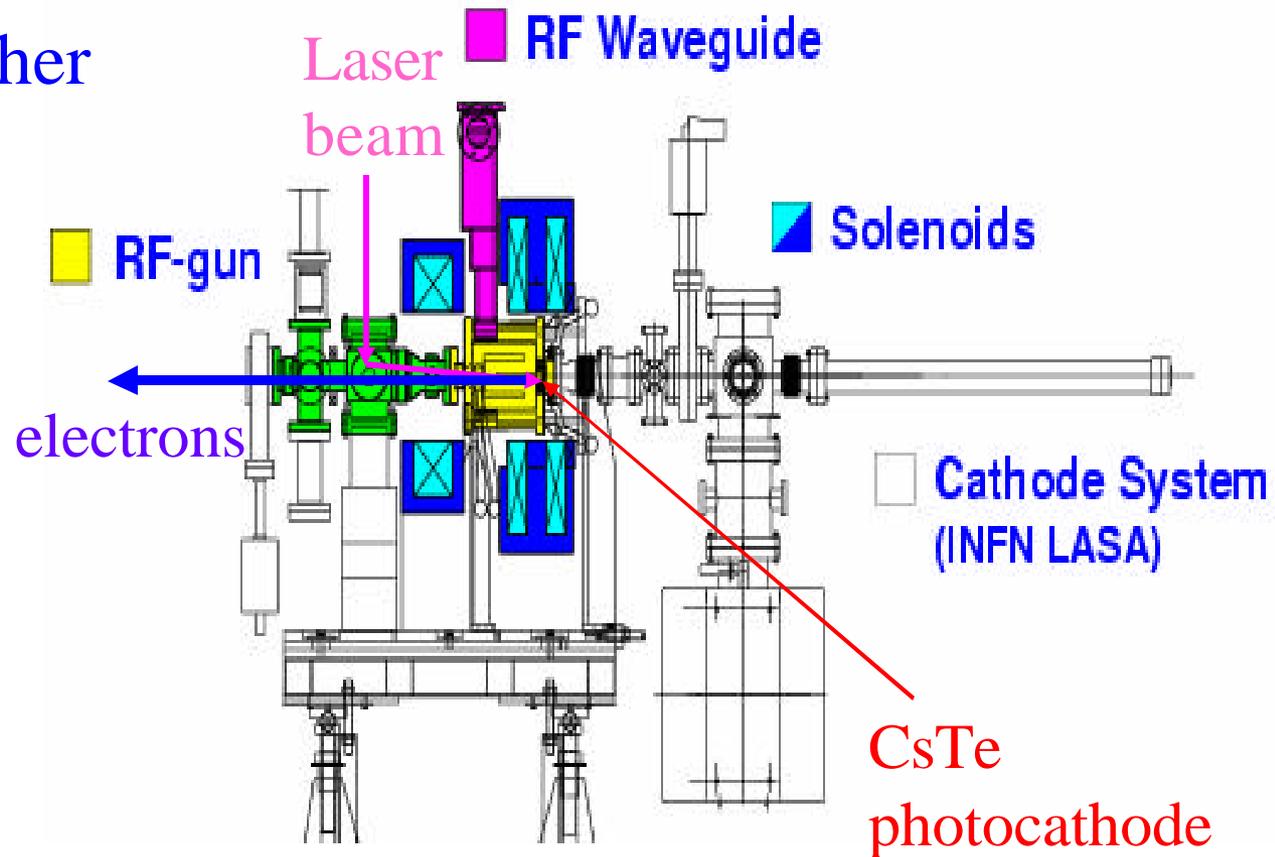
$I_{\text{peak}} = 200\text{-}1700 \text{ A (BC on)}$



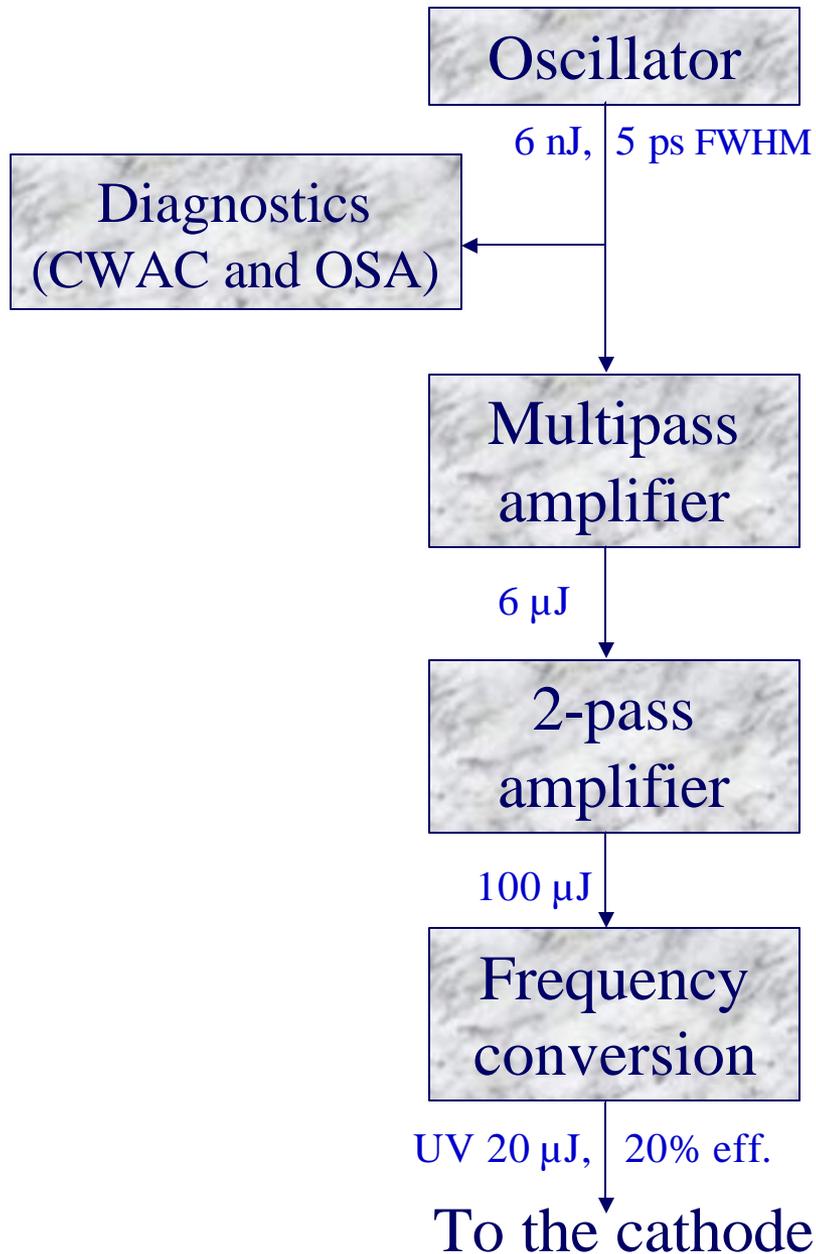
GENERATION OF ELECTRONS:

At A0 photoemission is used since it enables the production of higher charge density

- ?CsTe photocathode requires uv light
- ?Laser energy needed:
few μJ to produce up to 20 nC charge



A0 DRIVE LASER



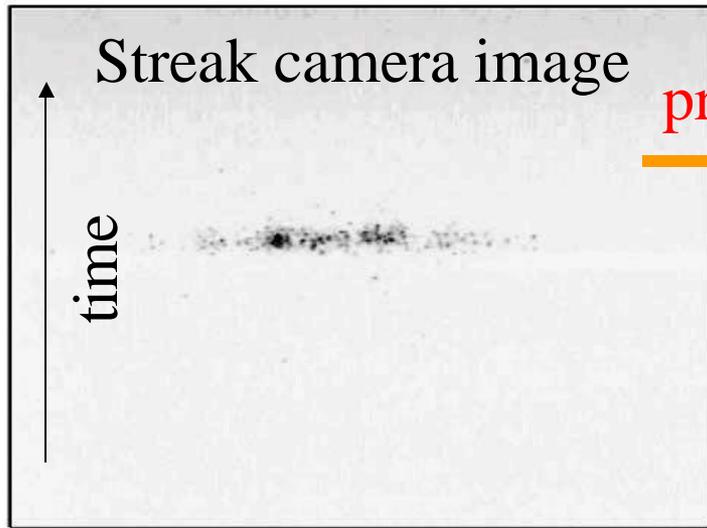
-Nd:YLF oscillator, 1054 nm, 0.5 W, 81.25 MHz pulse train

-Nd:glass amplifier, 6 round-trips, 1 MHz pulse train (1-800 pulses), amplifies up to 2000 times, 5% shot-to-shot amplitude fluctuation

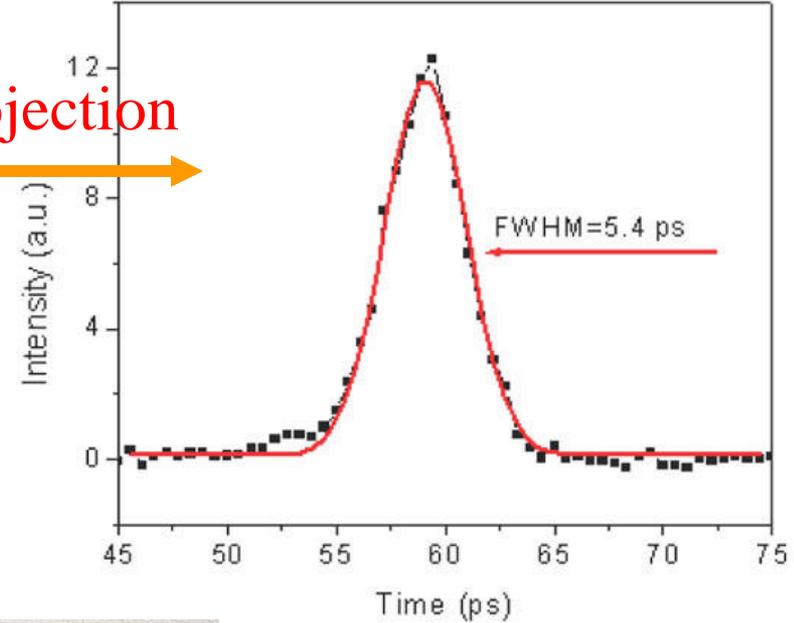
-Nd:glass amplifier, 1 round-trip through double laser head, amplifies up to 70 times

-2 BBO 10 mm crystals, 50% IR to green efficiency, 40% green to UV efficiency

A0 DRIVE LASER: OSCILLATOR



projection

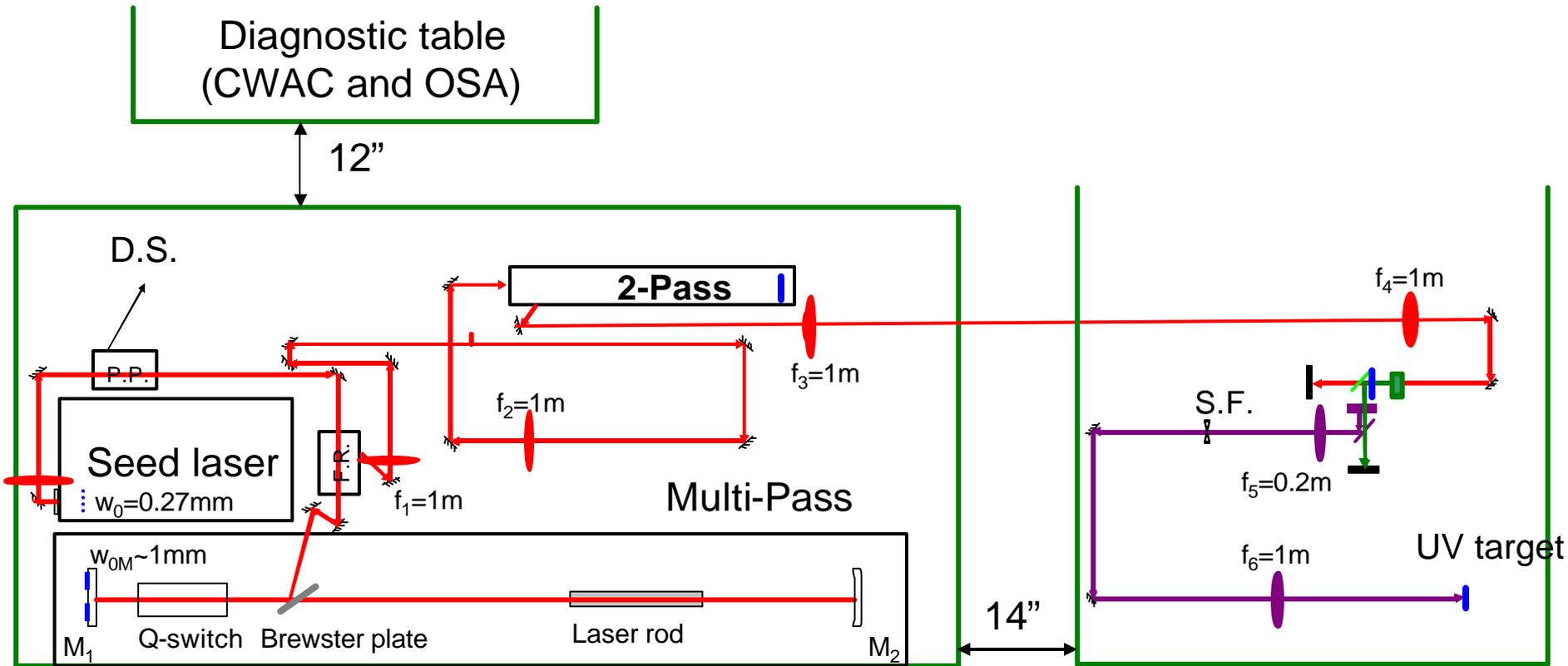


Oscillator is a commercial device



seed laser output:
wavelength: 1.053 μm
power: 0.5 W,
duration: 5ps
(FWHM).

A0 DRIVE LASER

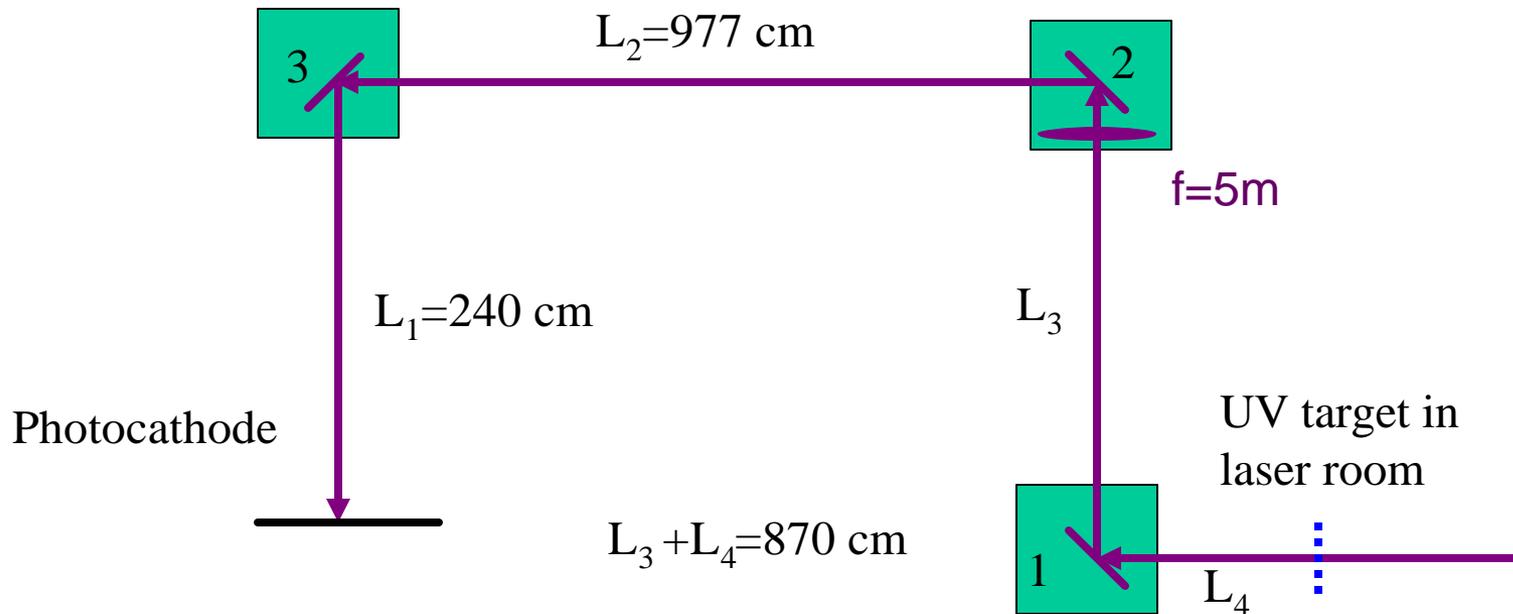


A0 laser system schematic.

A0 DRIVE LASER

The location of the laser room is 20 meter from the accelerator enclosure

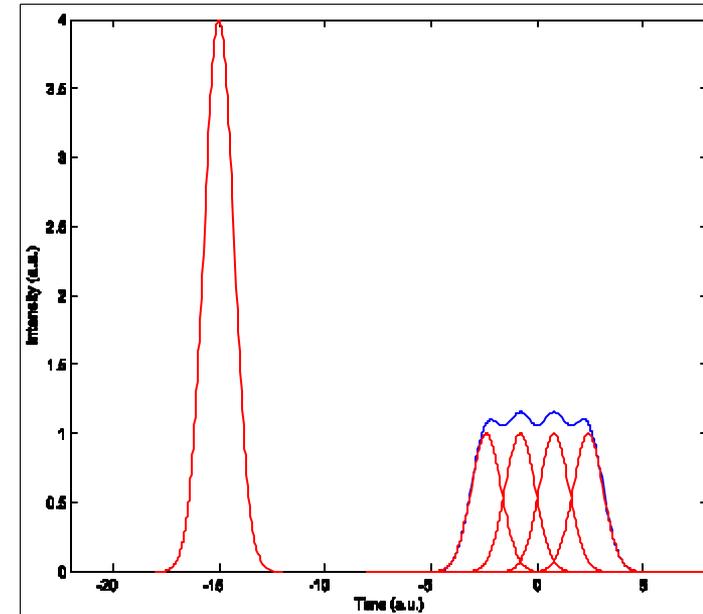
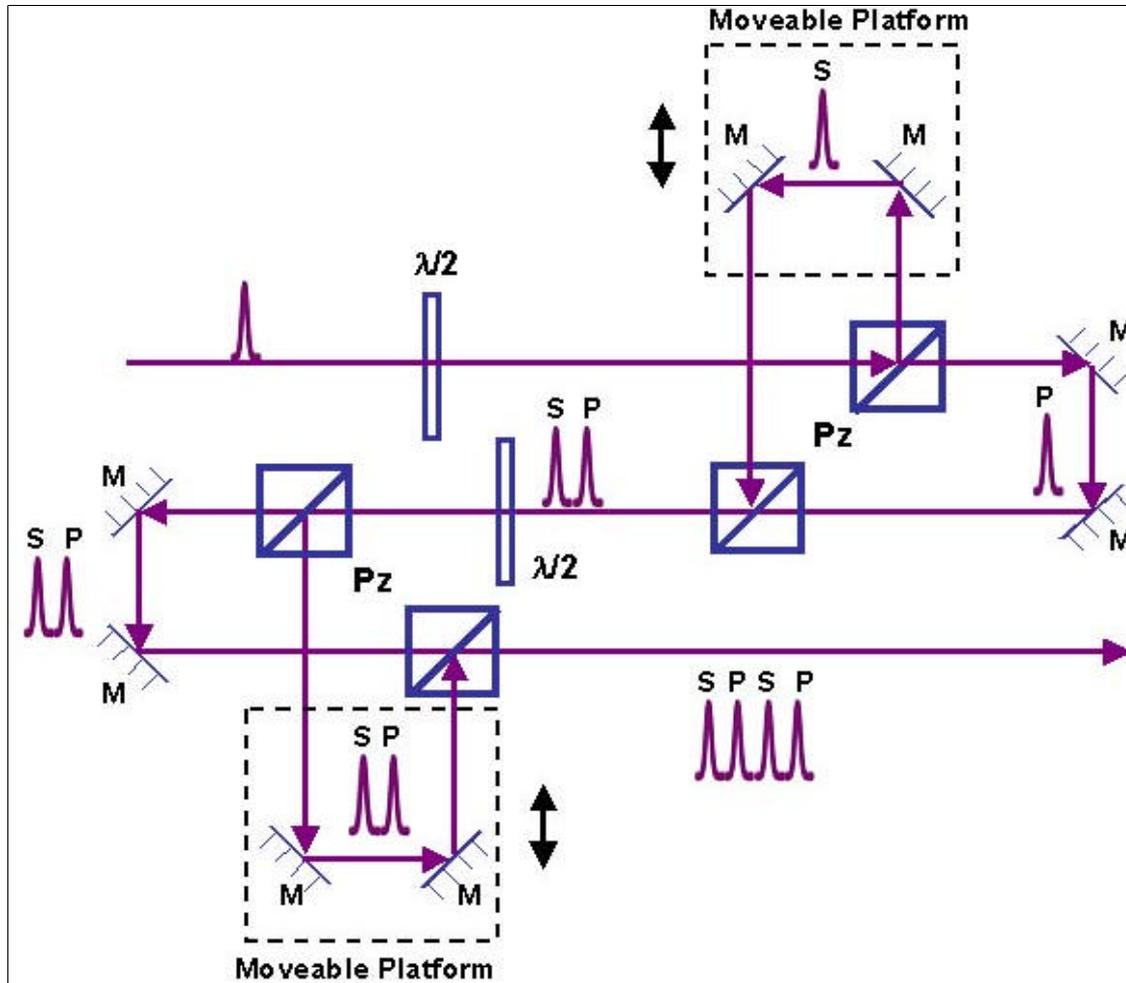
A relay-imaging system was installed to transport the laser beam from the laser room to the photocathode system



Laser-to-Cathode Imaging System

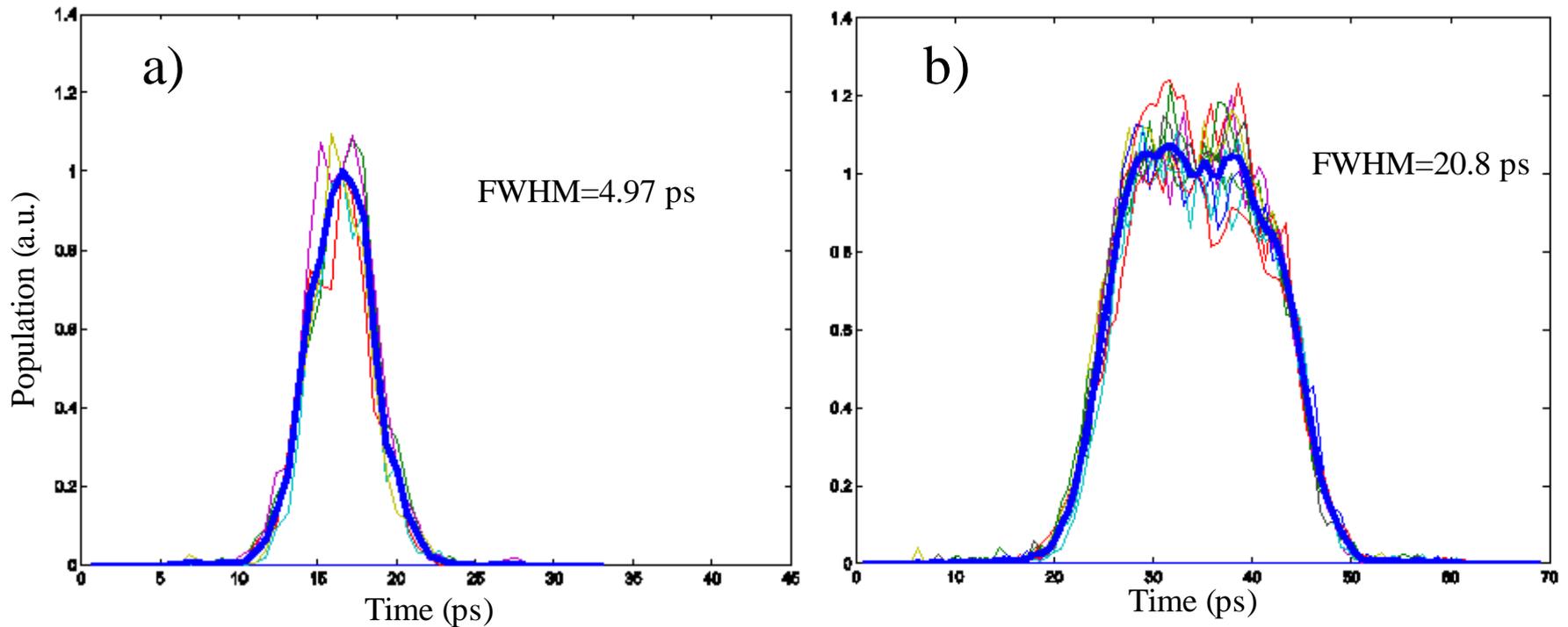
A0 LASER TEMPORAL SHAPING

To reduce the space charge effect, a square pulse in longitudinal domain should be used.



- “flat-top” pulse generated using a pulse stacking scheme
- polarization flipping avoids interferences

PHOTOINJECTOR LASER TEMPORAL SHAPING



Streak camera images of **a)**: single and **b)**: stacked (four) pulses.

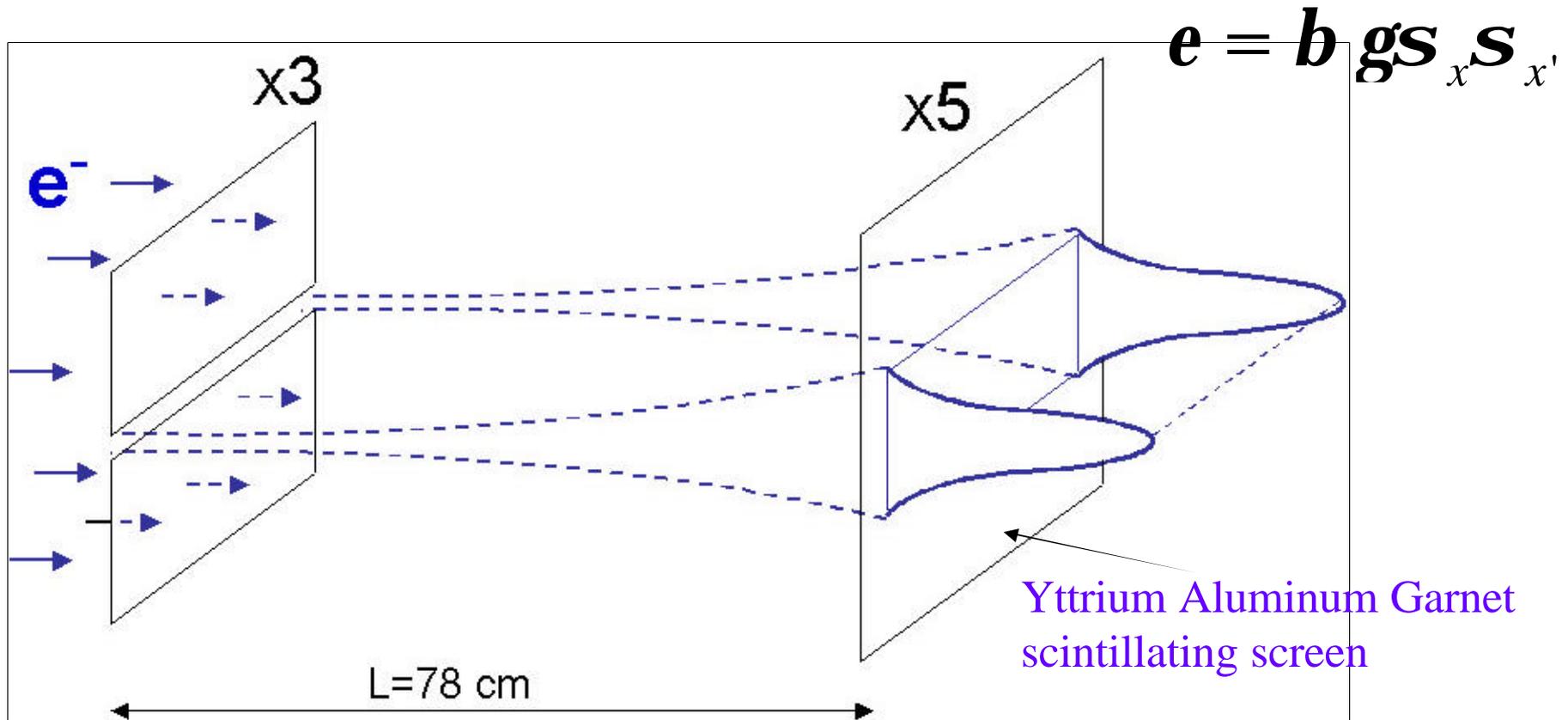
EMITTANCE

- According to Liouville's theorem, the volume of an ensemble of non-interacting particles in a six-dimensional phase space (\vec{r}, \vec{p}) is invariant
- The statistical definition of transverse emittance is given by

$$\mathbf{e}_{n,x}^{rms} \equiv \frac{1}{mc} \sqrt{\langle x^2 \rangle \langle p_x^2 \rangle - \langle xp_x \rangle^2}, \quad (1)$$

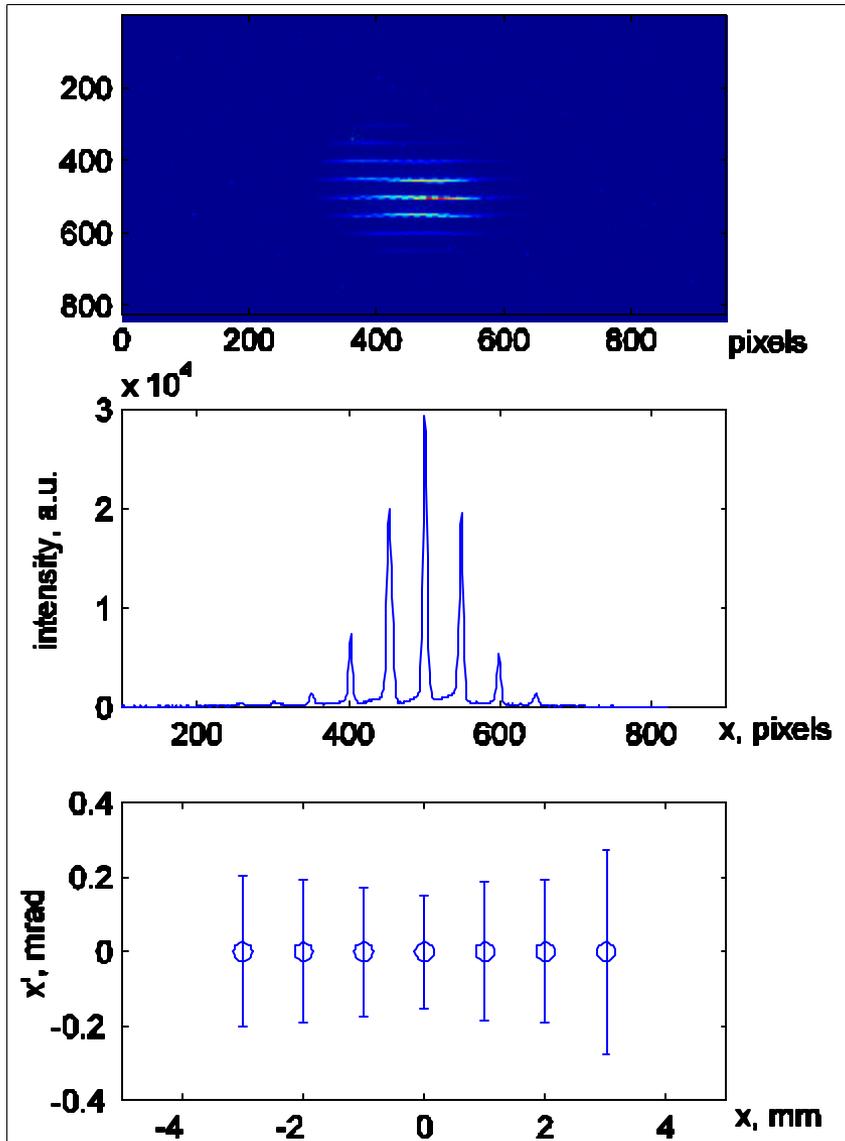
TRANSVERSE EMITTANCE MEASUREMENT

The slit technique was used to measure emittance:



The radiation is captured with a CCD camera focused on the YAG screen; the setup is installed downstream of the 9-cell cavity.

RESULTS: example of trace space measurement



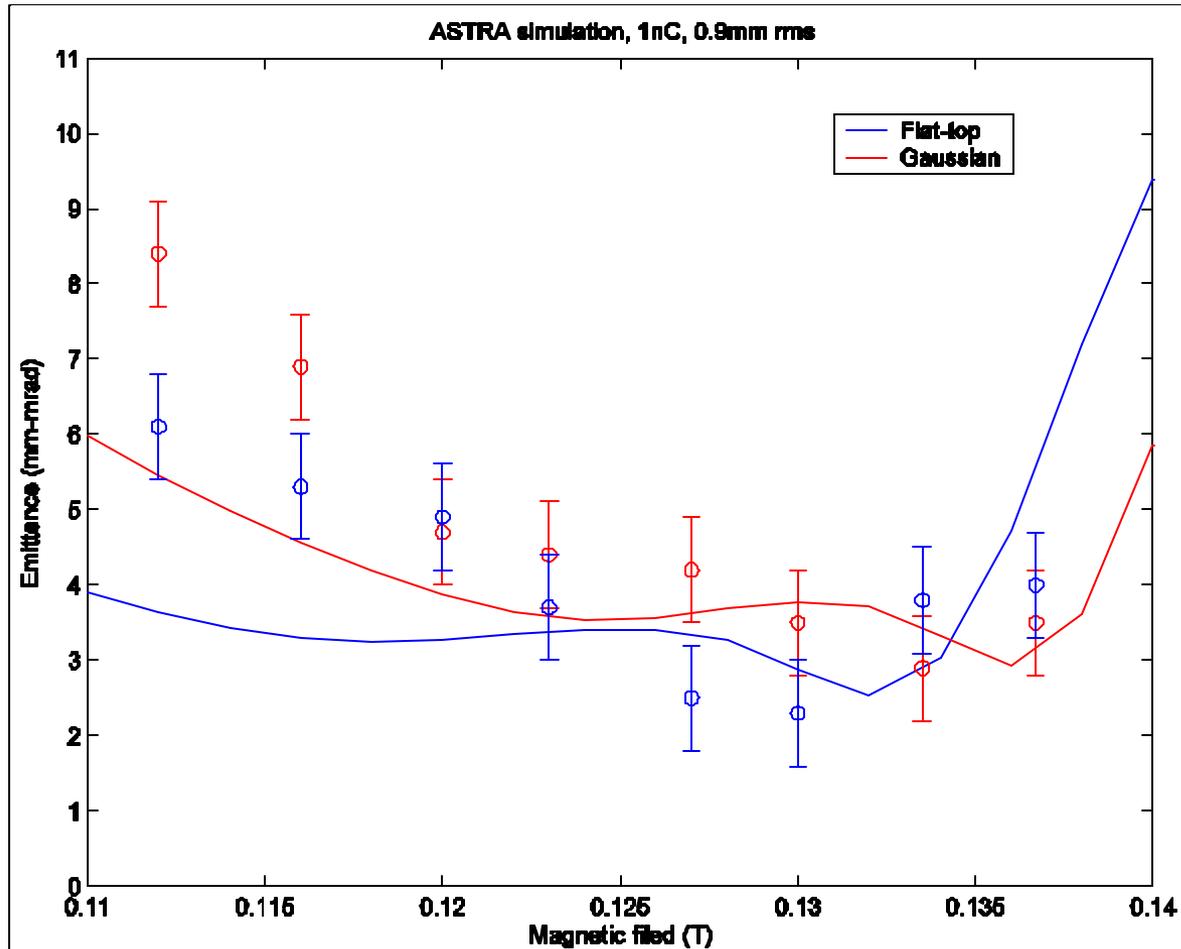
-Slits image at X5

-and its projection along x-axis.

- Measurement of divergence as a function of distance from the center.

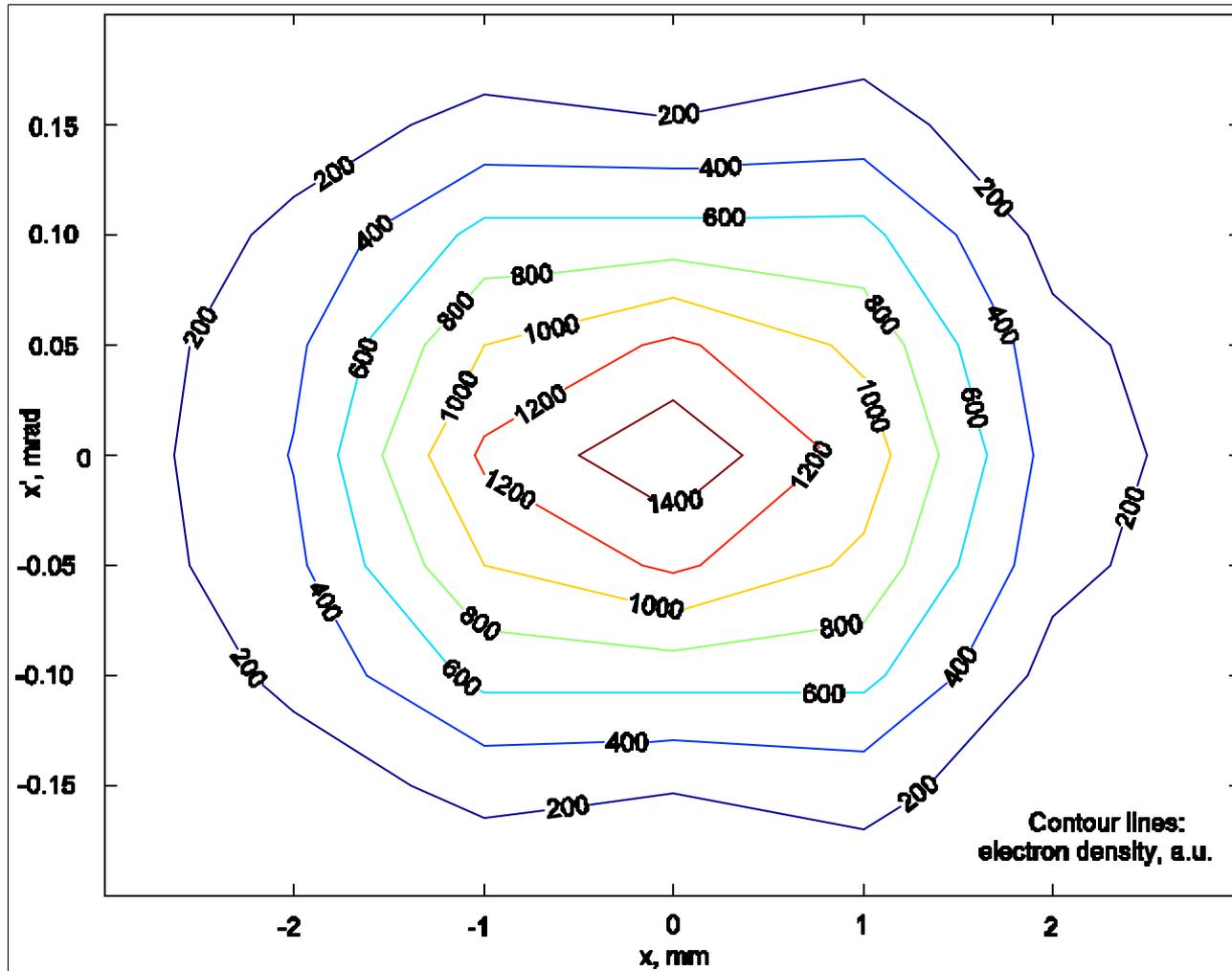
- Due to non-linear space charge effects on the edge of the beam, the divergence there is greater.

EMITTANCE MEASUREMENTS



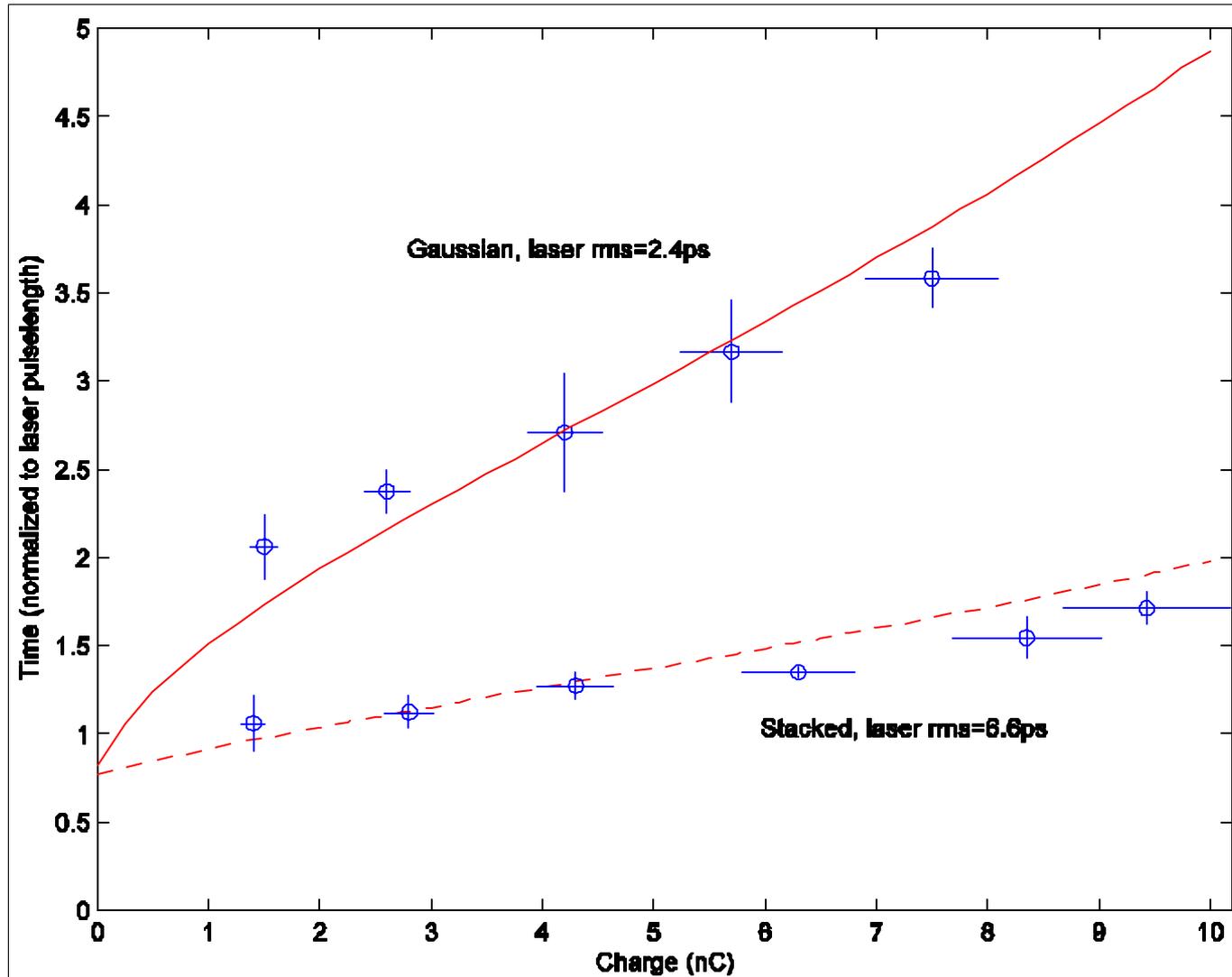
Emittance measurements after the 9-cell cavity; flat-top versus Gaussian laser pulse (1nC).

RESULTS



Transverse phase space map at x3; 1nC, flattop.

BUNCH LENGTH MEASUREMENTS



Electron bunch length as a function of charge.

RESULTS

- We have measured the emittance for both Gaussian and flat-top pulses as a function of rf-gun solenoid current. The minimum value for a Gaussian pulse is 3.0 mm-mrad (190A); and for stacked is 2.5 mm-mrad (200A). The stacked pulse has relatively lower emittance. This agrees well with the ASTRA simulation.
- The divergence of the beam was measured as a function of transverse distance. As expected the divergence is smallest in the center of the beam and it grows as we move away from the center (transversely).
- Electron bunch elongation as a function of charge was studied. The growth for the longer flattop is significantly slower.

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